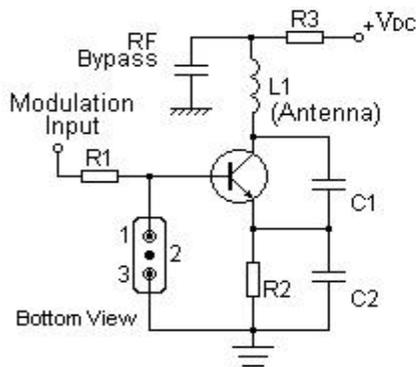


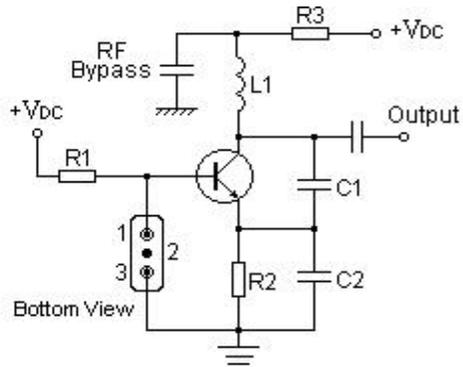
- 1-port Resonator
- Metal Case for **D11**
- Package size 8.36x3.45x3.00 mm³
- **RoHS** compatible
- **Electrostatic Sensitive Device(ESD)**

Application

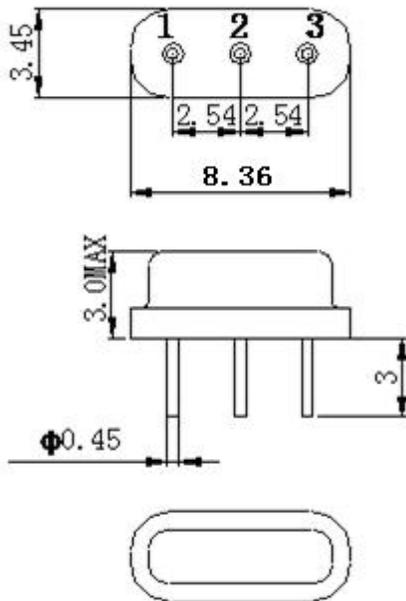
Typical Low-Power Transmitter Application



Typical Local Oscillator Application



Package Dimensions (D11)



Pin Configuration

1	Input/output
3	Output/Input
2	Case Ground

R	SAW Resonator
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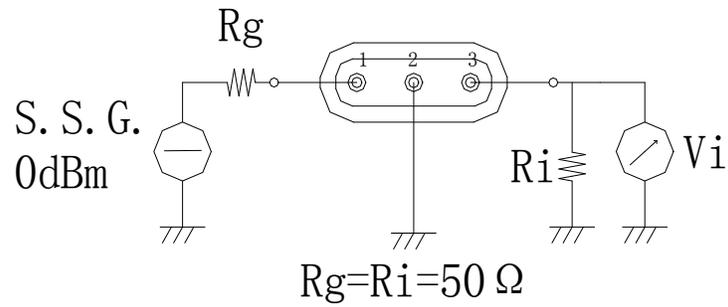
Marking

433

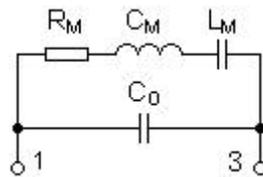
Part number



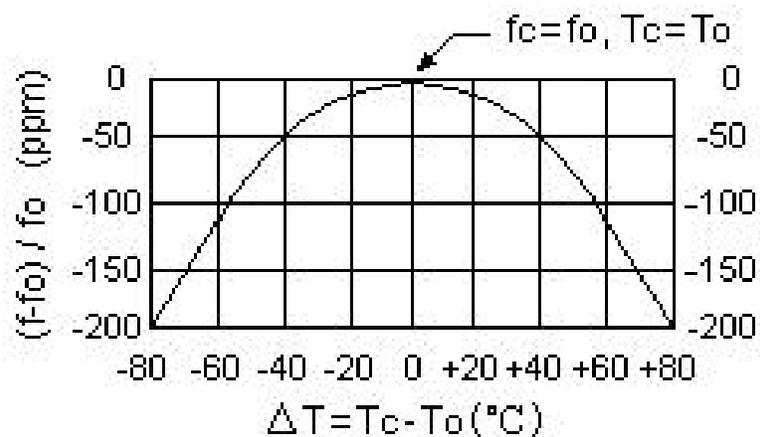
Test Circuit



Equivalent LC Model



Temperature Characteristics



The curve shown above accounts for resonator contribution only and does not include LC component temperature contributions.

Performance**Maximum Rating**

Item		Value	Unit
DC Voltage	V_{DC}	± 30	V
Operation Temperature	T	-40 ~ +85	°C
Storage Temperature	T_{stg}	-55 ~ +125	°C
RF Power Dissipation	P	10	dBm

Electronic Characteristics

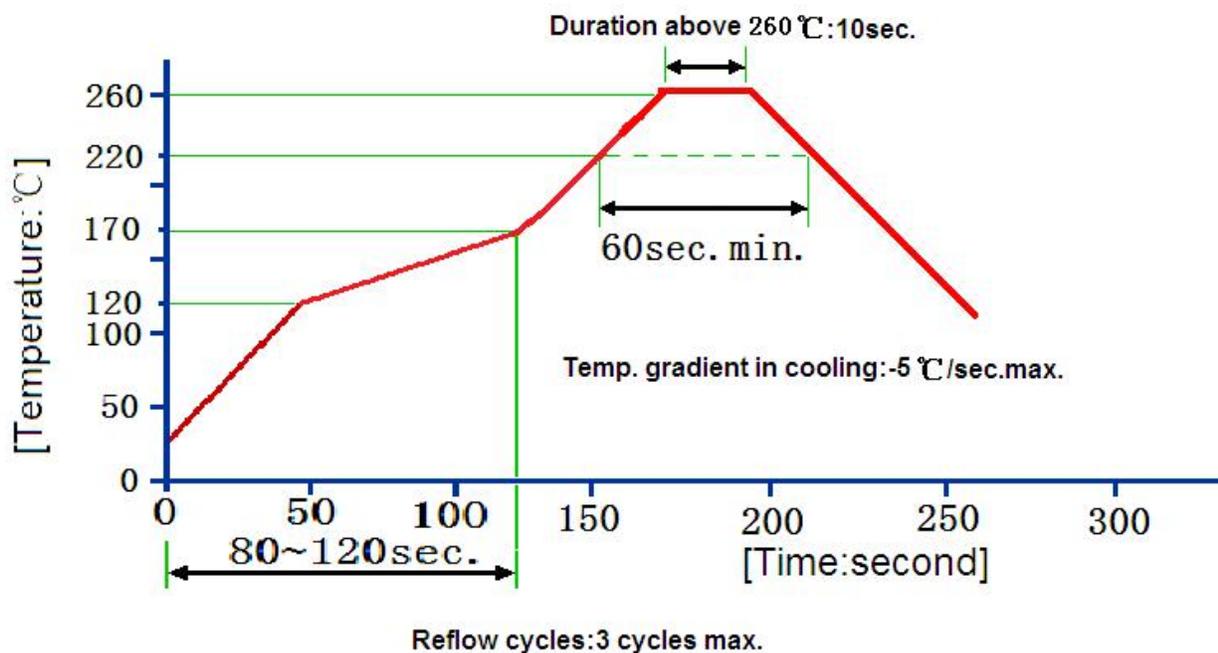
Test Temperature: $25^{\circ}\text{C} \pm 2^{\circ}\text{C}$

Terminating source impedance: 50Ω

Terminating load impedance: 50Ω

Item			Minimum	Typical	Maximum	Unit
Center Frequency	Absolute Frequency	f_c		433.92		MHz
	Tolerance from 433.92MHz	Δf_c		± 75		KHz
Insertion Loss(min)		IL		1.4	2.0	dB
Quality Factor	Unloaded Q	Q_U		14215		
	50Ω Loaded Q	Q_L		1791		
Temperature Stability	Turnover Temperature	T_0	10	25	40	°C
	Turnover Frequency	f_0		f_c		KHz
	Frequency Temperature Coefficient	FTC		0.032		ppm/°C
Frequency Aging	Absolute Value during the First Year	$ f_A $		≤ 10		ppm/yr
DC Insulation Resistance between Any Two Pins			1.0			MΩ
RF Equivalent RLC Model	Motional Resistance	R_M		15	26	Ω
	Motional Inductance	L_M		98.9		μH
	Motional Capacitance	C_M		2.35		fF
	Static Capacitance	C_0	2.8	3.1	3.4	pF

Recommended Reflow Soldering Diagram



Notes

1. As a result of the particularity of inner structure of SAW products, it is easy to be broken down by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.